

Notice of References Cited

Application/Control No.

09/862,557

Applicant(s)/Patent Under

Reexamination
KIKUCHI, HIROKI

Examiner

Virginia M Kibler

Art Unit

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Komatsu et al., "A new auto-focus method in critical dimension measurement SEM," IEEE 1997, pages 202-207.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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